	n Notes	

1	Application/Control No.	Applicant(s)/Patent u Reexamination	nder
	10/725,864	NAKAJIMA ET AL.	
	Examiner	Art Unit	
	Stephen M. Hepperle	3753	

SEARCHED			
Class	Subclass	Date	Examiner
137	484.8 505.18 505.37	10/05	SIMP
429	22		
<u>429</u>	Search	5/06	SA
429	25	5/06 8/0c	SA
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see al	ronce	8/06	900
see roh	shoet		·

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
CI 429–consulted Ex Ryan	10/05	Spo
EAST	10/05	9 4
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